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- A.E.M.J. Fischer, W.F.J. Slijkerman, J.F. van der Veen and I. Ohdomari, Thermal stability of supersaturated oxygen-doped silicon epitaxial films
- V.V. Tokarev, A.V. Kibardin, T.M. Pyatkova and D.I. Zarovsky, Nickel, cobalt and iron silicide formation stimulated by argon implantation
- S. Priggemeyer, A. Brockmeyer, H. Dötsch, H. Koschmieder, D.J. O'Connor and W. Heiland, The segregation of Pb on yttrium-iron-garnet (YIG) surfaces studied by ion scattering spectrometry (ISS)

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- S.C. Tjong, Electrochemical and surface analysis of the Fe-Cr-Ru system in non-oxidizing acid solutions
- P. Lejček, M. Koutník, J. Brádler, V. Paidar and A. Potměšilová, Anisotropy of grain boundary segregation in as-grown Fe-6at%Si alloy bicrystals
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- S. Priggemeyer, A. Brockmeyer, H.
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